

**Search Notes**

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Examiner

Frank Duong

Applicant(s)/Patent under  
Reexamination

TAKANO ET AL.

Art Unit

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**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

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Interference Search (see printout)		10/29/2007	FD

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST Search (see printout)	10/29/2007	FD
Updated Inventorship (see printout)	10/29/2007	FD
Updated IEEE/Internet Search	10/29/2007	FD